

EV 182659599

Sheet 1 of 8

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
M122-2037SERIAL NO.
09/945,508LIST OF ART CITED BY APPLICANT
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APPLICANT: Kei-Yu Ko

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U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate
LJN-E	AA 4,381,201	04/26/83	Sakurai	148	1.5	
LJN-E	AB 4,472,729	09/18/84	Shibata et al.	357	49	
LJN-E	AC 4,489,478	12/25/84	Sakurai	29	574	
LJN-E	AD 4,681,657	07/21/87	Hwang et al.	156	657	
LJN-E	AE 4,753,709	06/28/88	Welch et al.	156	643	
LJN-E	AF 4,807,016	02/21/89	Douglas	357	67	
LJN-E	AG 4,818,335	04/04/89	Karnett	156	644	
LJN-E	AH 4,966,865	10/30/90	Welch et al.	437	192	
LJN-E	AI 5,037,777	08/06/91	Mele et al.	437	195	
LJN-E	AJ 5,063,169	11/05/91	DeBruin et al.	437	41	
LJN-E	AK 5,084,417	01/28/92	Joshi et al.	437	192	

FOREIGN PATENT DOCUMENTS

Document Number	Date	Country	Class	Subclass	Translation
					Yes No
LJN-E AL 56-114355	09.08.81	Japan (Yoji)			Abstract
LJN-E AN 60-42821	03.07.85	Japan (Mitsubishi Electric Corp)			Abstract
LJN-E AM 61-133555	12.09.86	Japan (Varta Batterie)			X
LJN-E AO 0 265 584 A2	05.05.87	EPO (IBM)			

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

LJN-E	AP	Abatchev et al., Study of the Boron-Phosphorous Doped and Undoped Silicate Glass Etching in CHF ₃ /Ar Plasma, 96 ELECTROCHEM SOC. PROCEEDINGS, No. 12, pp. 522-530 (1996).
LJN-E	AD	Ikegami et al., Mechanisms of High PSG/SiO ₂ Selective Etching in a Highly Polymerized Fluorocarbon Plasma, 30 JAP. J. APPL. PHYS., No. 7, pp. 1556-1561 (July 1991).

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Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate
LJME	AA	5,150,276	09/22/92	Gonzalez et al.	361	313	
LJME	AB	5,192,703	03/09/93	Lee et al.	437	52	
LJME	AC	5,208,176	05/04/93	Ahmad et al.	437	47	
LJME	AD	5,210,047	05/11/93	Woo et al.	437	43	
LJME	AE	5,252,517	10/12/93	Bialock et al.	437	195	
LJME	AF	5,286,344	02/15/94	Bialock et al.	156	657	
LJME	AG	5,298,465	03/29/94	Levy	437	225	
LJME	AH	5,312,768	05/17/94	Gonzalez	437	40	
LJME	AI	5,321,286	06/14/94	Koyama et al.	257	315	
LJME	AJ	5,323,047	06/21/94	Nguyen	257	384	
LJME	AK	5,362,666	11/08/94	Dennison	437	52	

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
LJME	AL	0 465 044 A2	19.06.91	EPO (AT&T)				
LJME	AM	4-345054	12.01.92	Japan (Ricoh Co.)			X	
LJME	AN	0 498 614 A1	23.01.92	EPO (NEC Corp.)				
LJME	AO	4-360570	14.12.92	Japan (Mitsubishi Electric Corp.)			Abstract	

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

LJME	AP	van den Hoek et al., <i>Isotropic plasma etching of doped and undoped silicon dioxide for contact holes and vias</i> , 7 J. VAC. SCI. TECHNOL., No. 3, pp. 670-675 (May/June 1989).
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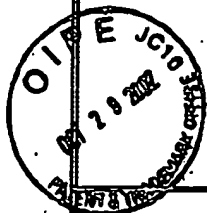
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Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate
LJTHE	AA	5,388,590	11/22/94	Kadomura	156	662	
LJTHE	AB	5,374,332	12/20/94	Koyama et al.	156	643	
LJTHE	AC	5,401,681	03/28/95	Dennison	437	60	
LJTHE	AD	5,422,308	06/06/95	Nicholls et al.	437	192	
LJTHE	AE	5,423,945	06/13/95	Marks et al.	156	662.1	
LJTHE	AF	5,429,070	07/04/95	Campbell et al.	118	723	
LJTHE	AG	5,445,712	08/29/95	Yanagida	156	662	
LJTHE	AH	5,478,772	12/26/95	Fazan	437	60	
LJTHE	AI	5,482,894	01/09/96	Havemann	437	195	
LJTHE	AJ	5,485,035	01/16/96	Lin et al.	257	637	
LJTHE	AK	5,550,071	08/27/96	Ryou	437	41	

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		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
LJTHE	AL	5-335482	17.12.93	Japan (Semiconductor Energy)			Abstract	
LJTHE	AM	0 680 084 A1	28.04.95	EPO (Texas Instruments, Inc.)				
LJTHE	AN	0 763 850 A1	30.08.96	EPO (Applied Materials, Inc.)				
LJTHE	AO	WO 98/49719	05.11.98	WIPO (Micron Technology, Inc.)				

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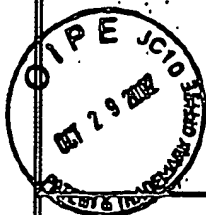
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Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate
L.T.M.E.	AA	5,611,888	03/18/97	Bosch et al.	156	643.1	
L.T.M.E.	AB	5,626,716	05/08/97	Bosch et al.	438	723	
L.T.M.E.	AC	5,643,819	07/01/97	Tseng	437	60	
L.T.M.E.	AD	5,677,227	10/14/97	Yang et al.	437	60	
L.T.M.E.	AE	5,685,914	11/11/97	Hills et al.	118	723	
L.T.M.E.	AF	5,685,951	11/11/97	Torek et al.	156	646.1	
L.T.M.E.	AG	5,700,731	12/23/97	Lin et al.	438	381	
L.T.M.E.	AH	5,712,202	01/27/98	Liaw et al.	438	253	
L.T.M.E.	AI	5,731,130	03/24/98	Tseng	430	316	
L.T.M.E.	AJ	5,731,242	03/24/98	Parat et al.	438	586	
L.T.M.E.	AK	5,736,455	04/07/98	Iyer et al.	138	592	

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Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
L.T.M.E.	AA	5,747,369	05/05/98	Kantimahanti et al.	438	241	
L.T.M.E.	AB	5,780,338	07/14/98	Jeng et al.	438	253	
L.T.M.E.	AC	5,783,496	07/21/98	Flanner et al.	438	743	
L.T.M.E.	AD	5,792,689	08/11/98	Yang et al.	438	253	
L.T.M.E.	AE	5,792,703	08/11/98	Bronner et al.	438	620	
L.T.M.E.	AF	5,817,579	10/06/98	Ko et al.	438	740	
L.T.M.E.	AG	5,821,594	10/13/98	Kasai	257	410	
L.T.M.E.	AH	5,851,896	12/22/98	Summerfelt	438	396	
L.T.M.E.	AI	5,871,659	02/16/99	Sakano et al.	216	79	
L.T.M.E.	AJ	5,883,436	03/16/99	Sadjadi et al.	257	760	
L.T.M.E.	AK	5,897,352	04/27/99	Lin et al.	438	255	

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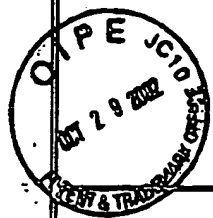
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L.J.M.E.	AA	5,918,120	06/29/99	Huang	438	239	
L.J.M.E.	AB	5,936,272	08/10/99	Lee	257	306	
L.J.M.E.	AC	5,946,568	08/31/99	Hsiao et al.	438	253	
L.J.M.E.	AD	5,986,299	11/16/99	Nakamura et al.	257	296	
L.J.M.E.	AE	5,990,507	11/23/99	Mochizuki et al.	257	295	
L.J.M.E.	AF	6,074,488	06/13/00	Roderick et al.	118	728	
L.J.M.E.	AG	6,074,958	06/13/00	Tokunaga et al.	438	724	
L.J.M.E.	AH	6,117,788	09/12/00	Ko	438	706	
L.J.M.E.	AI	6,117,791	09/12/00	Ko et al.	438	723	
L.J.M.E.	AJ	6,121,671	09/19/00	Ko et al.	257	644	
L.J.M.E.	AK	6,124,199	09/26/00	Bohr	438	595	

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L.T.H.E.	AA	6,153,490	11/28/00	Xing et al.	438	396	
L.T.H.E.	AB	6,159,862	12/12/00	Yamada et al.	438	712	
L.T.H.E.	AC	6,165,880	12/26/00	Yaung et al.	438	592	
L.T.H.E.	AD	6,171,970 B1	01/09/01	Xing et al.	438	706	
L.T.H.E.	AE	6,174,451 B1	01/16/01	Hung et al.	216	67	
L.T.H.E.	AF	6,183,655 B1	02/06/01	Wang et al.	216	68	
L.T.H.E.	AG	6,242,759 B1	08/05/01	Yamazaki et al.	257	69	
L.T.H.E.	AH	6,271,542 B1	08/07/01	Emma et al.	257	67	
L.T.H.E.	AI	6,277,758 B1	08/21/01	Ko	438	706	
L.T.H.E.	AJ	6,337,285 B1	01/08/02	Ko	438	714	
L.T.H.E.	AK	6,432,833 B1	08/13/02	Ko	438	714	

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L. JONE	AA 6,458,685 B2	10/01/02	Ko et al.	438	621	
L. JONE	AB 08/846,671		Ko (as filed and as amended)			04/30/1997
L. JONE	AC 09/532,088		Ko (as filed)			03/21/2000
L. JONE	AD 09/579,402		Ko (as filed and as amended)			05/25/2000
	AE					
	AF					
	AG					
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